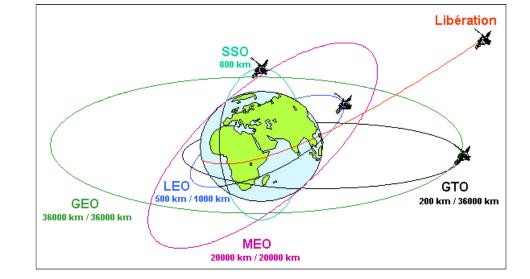
# **Atmel**

### Space components vs parts for automotive applications



ESCCON 1-3 March 2016

### Content

- Automotive methodology overview
- Space vs. Automotive qualification methodologies comparison
- Quality targets
- Ways forward



## **Automotive business model**

Car Makers continuously challenging IC suppliers...

... to establish quality in the market place

#### Share of electronic components

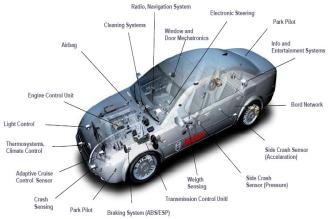
- Electronic modules: 50
- Components: 300/module
- Overall: 15000/car

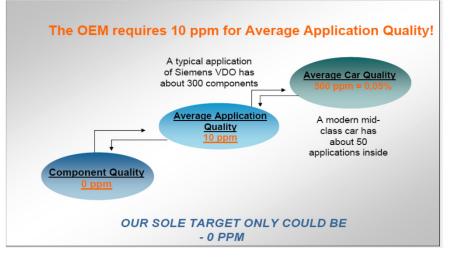
#### **Design complexity**

- Time to market: 2-3 years
- System options/car type
- Various cars
- Numerous soft variants
- ISO-26262: Functional safety of road vehicles

#### Life cycle

- Car series: 5/8 years
- Spare parts: 10-15 years
- Component longevity: 5/8 years



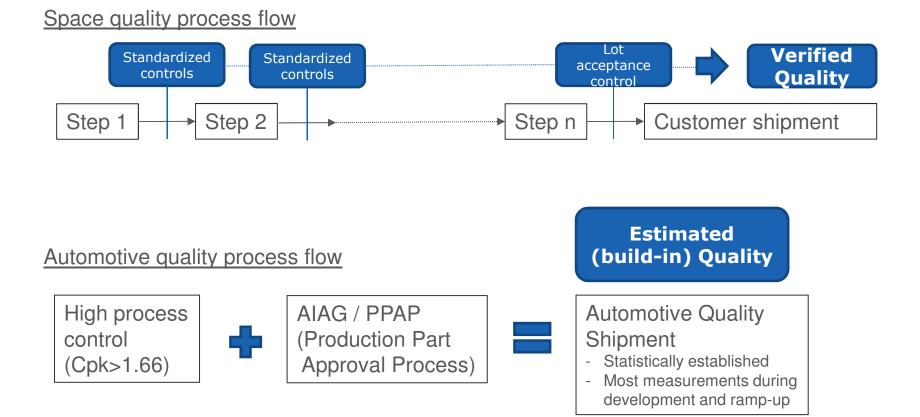




# **Automotive Quality Assurance**

Robustness to harsh environment...

... at cost of industrial products

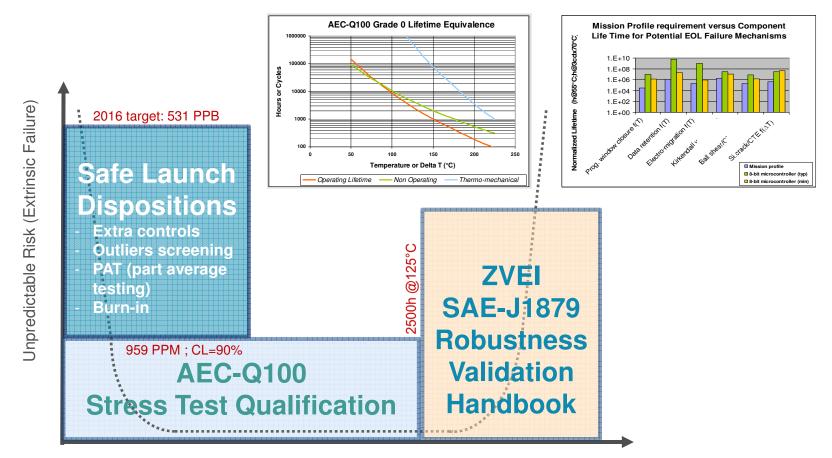




# High Reliability / Zero Defects in the cars

AEC-Q100 is the qualification baseline ...

... but Zero Defects goals require extended assessment methods

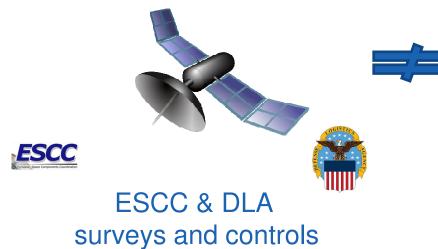


Predictable Risk (Intrinsic Failure)





Policies



- Organization
   & survey committees
- Set of requirement specifications and test methods
- Qualification certificate for a specific domain
- Periodical survey audits from space agencies



Customer/Manufacturer mutual agreement

- Nothing equivalent
- AEC-Q100 & JESD
- Mutual qualification (Manufacturer/Customer)
- Customer audits



Product Qualification (1/2)







#### Long lifetime

*3 wafer lots Preceded by an evaluation lot* 

- Wearout reliability tests
  @20 years at 110°C
- Electrical: ESD CDM/HBM, LU
- SEM (each wafer lot)
- Internal visual inspections
- TID/SEE
- 7 © 2016 Atmel Corporation

# Lifetime application dependent

*3 wafer lots Also some evaluation tests* 

- 15 years @85°C / 15% operating
- Same
- N/A
- N/A
- N/A



Product Qualification (2/2)



### **Visual Inspections**

- Life test 2000h/125°C
- Specific tests for NVM (cycling, endurance...)
- Packaging/assembly tests
  - Ceramic
  - Plastic
- External Visual Inspections



### Automatic inspections

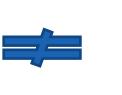
- Equivalent 1000h/125 or 150°C (> in terms of device-hours)
- Equivalent

- N/A
- Equivalent (except outgassing)
- Automatic



Documentation/data control





- TRB set up by the company, including
  - Change Notification System
  - Qualification monitoring review
  - Customer returns analysis...
- Periodical reporting to agencies
- Agency alert system

9

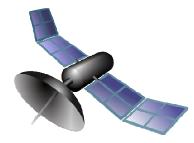
- Qualification package and Radiation report
- Each Flight Model delivery done with data package (screening data and qualification summary)
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 Change Notification System vs AEC-Q100

- N/A
- N/A
- PPAP
- NA



### **Quality targets**





- Quality by inspections
- Small qualification sampling
- Temp. Range -55/125°C
- 20 years at 110 °C
- Radiation hardening

- Quality by process control
- Large qualification sampling
- Temp. Range -40/125°C
- Typical = 15 years at 85 °C
- No radiation tolerance



### Level 1: reuse of Automotive parts for Space

- Use "as is"
- No design change
- Use Automotive part manufacturing flows
- Additional qualification & up-screening



Material out-gassing Radiation testing

Additional screening tests upon request

Leverage on automotive quality commitments
 Low cost

- □ No Space specific IP
- No space specification
- ❑ Lower temperature range
- □ No / low radiation tolerance
- □ Lead-free terminals



# Level 2: upgrading existing Automotive products for Space

Wafer Processing: Automotive technology enhanced for SEL free	<ul> <li>Long technology life time</li> <li>Repeatability</li> <li>Capability</li> </ul>	<ul> <li>Temperature range</li> <li>TID</li> </ul>
Packaging: ceramic hermetic	<ul> <li>Fits Space qualification standards</li> <li>In line inspections</li> </ul>	> Cost

- → ATMEGAS128 radiation tolerant product
  - CQFP64 and TQPF64 package
  - $\succ$  SEL = 60 Mev.cm<sup>2</sup>/mg
  - $\succ$  TID = 30 krad (evaluation)
  - $\succ$  Qualification = Jun-16



# Level 3: upgrading Automotive designs for Space



→ ARM M7 micro-controller SAMV71RHBD		
$\succ$	Automotive SAM7 platform	
$\succ$	Adding 1553 and Space Wire	
$\succ$	On ATMX150RHA	
	<ul> <li>Latch-up free</li> </ul>	
	<ul> <li>TID = 300 krad tested</li> </ul>	
$\succ$	Ceramic or plastic packaging options	
$\succ$	Samples on Q1-17	
L		



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